Bureau
International des
Poids et
Mesures

CCEM workshop on “Radiofrequency and microwave metrology: recent developments and challenges” to be held at the BIPM, 27 March 2019

Venue: Pavillon du Mail, BIPM, Sèvres, France

Workshop Programme

9:00	Opening by Markus Zeier, chair of the CCEM working group on radio-frequency quantities, GT-RF
9:20	“*S-Parameter measurements in coaxial systems*", Johannes Hoffmann, METAS, Switzerland
10:10	"*Plasmonic and photonic technologies for mm-wave wireless communications*", Maurizio Burla, ETH Zürich, Switzerland
11:00	Coffee break
11:40	“*Industrial metrology challenges induced by 5G"*, Michael Dieudonné, Keysight Technologies, Belgium
12:30	Lunch
13:30	"*Application of Modern Quasi-Optical Design and Manufacturing Techniques to mm-wave Remote Sensing Applications - both Active and Passive*", Richard Wylde, Thomas Keating Ltd, UK
14:20	"*High frequency characterization at sub-micrometer scales using on-wafer and scanning probe microscopy techniques*", Gilles Dambrine, Univ. of Lille, France
15:10	Tea break
15:40	"*Towards a quantum standard for radio-frequency electric fields*", Song Zhenfei, NIM, China
16:30	Closing discussion
17:00	End of workshop